

Application/Control	No.
10/695,147	

Examiner Tai Van Nguyen Applicant(s)/Patent under Reexamination
CHEN ET AL.

Art Unit 3729

				ISSUE	CL	.AS	SIF	ICAT	ION					
	-	ORIGINAL			INTERNATIONAL CLASSIFICATION									
CLASS SUBCLASS							CI	LAIMED		NON-CLAIMED				
29 890.1						21	D	53	/76		1			
		G	01	D	15	/00								
CLASS	SUBCL	ASS (ONE S	UBCLASS PE	R BLOCK)	Ľ			,,,			,			
29	830	831	832						1		1			
216	27								1		1			
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- Zau	A SE	XTE	Total Claims Allowed: 1											
(Legal Instruments Samipar) (Card) (Primary E							MINI	ER (Date)		O.G. Print Fig				
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C	Claims renumbered in the same order as presented by applicant							□ c	PA	 □ T.	D.	☐ R.1.47				
Final	Original	Final	Original		Final	Original		Final	Original		Final	Original	Final	Original	Final	Original
	1		31			61	1		91			121		151		181
	2		32			62]		92			122		152		182
	3		33			63]		93			123		153		183
	4		34			64]		94			124		154		184
	\$		5 5 5 7 3 8			65]		95			125		155		185
	6		36			66]		96			126		156		186
	7		37			67]		97			127		157		187
	8		_38			68	1		98			128		158		188
	9		39			69]		99			129		159		189
1	11		40			70]		100			130		160		190
2	11		41			71	1		101			131		161		191
3	12		42			72	Ì		102			132		162		192
	13		43			73	1		103			133		163		193
4 5	14		44			74	[104			134		164		194
6	15		45			75	1		105			135		165		195
7	16		46			76]		106			136		166		196
8	17		47			77	1		107			137		167		197
9	<u>(18)</u>		48			78	[108			138		168		198
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11	20		50			80]		110			140		170		200
12	21		51			81	1		111			141		171		201
13	22		52			82	1		112			142		172		202
14	23		53			83]		113			143		173		203
15	24		54			84]		114			144		174		204
16	25		55			85]		115			145		175		205
17	26		56			86]		116			146		176		206
	2		57			87]		117			147		177		207
	28		58			88	[118			148		178		208
	29		59			89]		119			149		179		209
	3b		60			90	1		120			150		180		210